

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

247456US2SRD

SERIAL NO.

New Application

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Keitaro SHIGENAKA, et al.

FILING DATE

Herewith

GROUP

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
CS	AO	9-284651	10/31/97	Japan		x
CS	AP	9-284561	10/31/97	Japan		x
CS	AQ	2002-286552	10/03/02	Japan (Corresponding to US Patent Application Serial Number 10/106,787)		x
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	X. GU, et al., "On-Chip Compensation of Self-Heating Effects in Microbolometer Infrared Detector Arrays", SENSORS AND ACTUATORS A, Vol. 69, 1998, pgs. 92-96				
	AX					
	AY					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached

Examiner

Date Considered

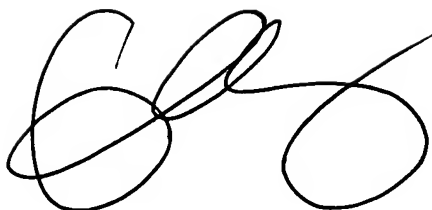
3/6/06

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

**LIST OF RELATED CASES**

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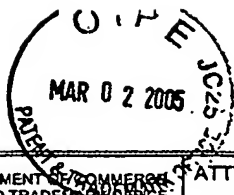
<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Inventor/ Applicant</u>
221314US2 TCRD	10/106,787	03/27/02	IIDA et al.



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(Modified)U.S. DEPARTMENT OF COMMERCE  
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ATTY DOCKET NO.

247456US2SRD

SERIAL NO.

10/753,386

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Keitaro SHIGENAKA, et al.

FILING DATE

January 9, 2004

GROUP

2878

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
CS	AO	2002-310783	10/23/2002	JAPAN		X
CS	AP	10-318843	12/04/1998	JAPAN		X
CS	AQ	7-35619	02/07/1995	JAPAN		X
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
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